

Fine-pitch probing with vertical probe cards on 3D stacked DUT

PA300PS 3D

300 mm Semi-automatic Probe System

Advanced EMI/RFI shielding

- Lowest spectral noise (< -170 dBVrms/rtHz)
- Lowest system AC noise (< 4 mVpp)
- Best shielding effectiveness (> 30 dB)
- Completely light tight

Vibration-free, spring-balanced EMI shield covers

- Instantaneous access to measurement setup
- DUT remains ice and condensation-free when open

Instrument shelf for easy access to measurement equipment

Automated Thermal Management™

- Provides temperature stability of all active devices like RSU, PreAmp or LFN amplifier
- Automated control depending on chuck temperature
- Fast reach of thermal equilibrium before testing
- ReAlign™ option to enable unattended tests at multiple temperatures

EMC² Guard™ Enclosure

- Patent-pending solution integrates large, sensitive measurement instrumentation
- Shortens cable lengths to DUT
- Eliminate investment for expensive shielded rooms
- Best-in-class 1/f measurements

Flexible feedthrough options

- Multiple locations for coaxial, triaxial and HF cables
- EMC compliant, light tight

MicroAlign™

- Performs ReAlign with off-axis pad-viewing camera
- Enables engineering tests with vertical probe cards
- The only solution for fine pitch probing down to 30 µm x 30 µm pads

Ergonomic low profile system design

Probe card adapter with integrated ProtecPlate™

- Extra shielding over the DUT
- No mechanical changeover needed for probe card use

AutoQuietMode™

- Eliminates noise by removing power from motorized stages
- Includes chuck stage, microscope stage and any motorized ProbeHeads
- Automatically engages when in contact

ProtecDrive™ II technology

- Shields all drive systems
- Lowest impedance grounding
- Best low-level measurements

Powerful ProberBench™ Operating Environment

- Stable, Linux-based controller
- Integrated, reliable industrial PC for running ProberBench software
- Quick integration with all test software from vendors such as Keithley and Agilent

Unique microscope solution

- High-stability microscope support
- Largest movement area within EMI/RFI-shielded environment
- Your choice of microscope from FS70 with four objectives to iVista™ High-Resolution Digital Microscope

Advanced software automation tools

- Patented Auto CalSite Alignment
- AutoAlign feature
- Powerful pattern recognition software

Patented ContactView™ system

- Visual contact monitoring to eliminate damage to wafers and probes
- ProbeHorizon™ sets a safe working distance and moves wafers into view automatically after loading

Large EMI/RFI-shielded enclosure

- Flexible measurement setup with up to 12 ProbeHeads™
- Use ProbeHeads and probe cards simultaneously in an EMI-shielded environment
- Integrate sensitive measurement equipment such as pre-amplifiers
- Shortest cable lengths

Seamless InteGration for Measurement Accuracy (SIGMA™)

- Ensures optimum measurement performance for all common and advanced measurement setups
- Easy to install and easy to use link between probes and the corresponding measurement equipment

Expert control panel

- Comfortable use without PC
- Full control of all probe stages with position feedback

Unique IntelliControl™ system control concept

- Entire system control from one panel
- Includes control of measurement equipment
- Analog joystick for precise, sub-micron positioning
- Point-and-shoot navigation
- Quick access to USB ports

Instant access to auxiliary chucks

- Located on forward position of loading mechanism
- Patented Auto CalSite Alignment detects the position of calibration substrates and automates the calibration procedure

Patented loading mechanism

- Keeps sensitive elements (chuck, stage) in place
- Reduces contamination to a minimum
- Reduces thermal conditioning times

Superior thermal performance from -60 °C to 300 °C

- Actively cooled platen reduces thermal drift
- New materials technology reduces conditioning times

Automated data generation

- Test routines run automatically with minimal operator intervention
- ReAlign™ Technology automatically adjusts alignment after every temperature change to compensate for thermal drift

Integrated vibration isolation system

- Eliminates vibration from external sources (acoustic, architectural, etc.)
- Enhances system stability
- Reduces damage to pads, wafers and probe tips

System height adjustable

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